

PROPERTIES OF SEMICONDUCTORS

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The term *semiconductor* is applied to a material in which electric current is carried by electrons or holes and whose electrical conductivity, when extremely pure, rises exponentially with temperature and may be increased from its low "intrinsic" value by many orders of magnitude by "doping" with electrically active impurities.

Semiconductors are characterized by an energy gap in the allowed energies of electrons in the material which separates the normally filled energy levels of the *valence band* (where "missing" electrons behave like positively charged current carriers "holes") and the *conduction band* (where electrons behave rather like a gas of free negatively charged carriers with an effective mass dependent on the material and the direction of the electrons' motion). This energy gap depends on the nature of the material and varies with direction in anisotropic crystals. It is slightly dependent on temperature and pressure, and this depen-

dence is usually almost linear at normal temperatures and pressures.

Data are presented in five tables. Table 1 lists the main crystallographic and semiconducting properties of a large number of semiconducting materials in three main categories: "Tetrahedral Semiconductors" in which every atom is tetrahedrally coordinated to four nearest neighbor atoms (or atomic sites) as for example in the diamond structure; "Octahedral Semiconductors" in which every atom is octahedrally coordinated to six nearest neighbor atoms—as for example the halite structure; and "Other Semiconductors."

Table 2 gives electrical, magnetic, and optical properties, while Tables 3 and 4 give more details on the semiconducting properties and band structure of the most common semiconductors. Table 5 lists semiconducting minerals with typical resistivity ranges.

TABLE 1. Physico-Chemical Properties of Semiconductors (Listed by Crystal Structure)

Substance	Molecular weight	Average atomic weight	Lattice parameters (Å, room temp.)	Density (g/cm ³)	Melting point (K)	Microhardness, N/mm ² (M-Mohs Scale)	Specific heat, J/kg·K (300 K)	Debye temp. (K)	Coefficient of thermal linear expansion [10 ⁻⁶ K ⁻¹ (300K)]	Thermal conductivity [mW/cm·K (300K)]
1.1. Adamantine Semiconductors										
<i>1.1.1. Diamond Structure Elements (Strukturbericht symbol A4, Space Group Fd3m-O_h²)</i>										
C (Diamond)	12.01	12.01	3.56683	3.513	≈4713 (12.4 GPa) Transition to graphite > 980	10 (M)	471.5	2340	1.18	9900(I) 23200(IIA) 13600(IIIB)
Si	28.09	28.09	5.43072	2.329	1687	11270	702	645	2.6	1240
Ge	72.64	72.64	5.65754	5.323	1211.35	7644	321.9	374	5.8	640
α-Sn	118.71	118.71	6.4912	5.769	505.1 (Tr. 286.4)		213	230	5.4 (220 K)	
<i>1.1.2. Sphalerite (Zinc Blende) Structure Compounds (Strukturbericht symbol B3 Space Group F⁻4̄3m-T_d²)</i>										
I-VII Compounds										
CuF	82.54	41.27	4.255		1181					
CuCl	98.99	49.49	5.4057	3.53	695	2.3 (M)	490	240	12.1	8.4
CuBr	143.45	71.73	5.6905	4.98	770	2.5 (M)	381	207	15.4	12.5
CuI	190.45	95.23	6.60427	5.63	878	192	276	181	19.2	16.8
AgBr	187.77	93.89		6.473	>1570 (Tr. 410)	2.5 (M)	270			
AgI	234.77	117.39	6.502	5.67	831	2.5 (M)	232	134	-2.5	4.2
II-VI Compounds										
BeS	41.08	20.54	4.865	2.36	dec.					
BeSe	87.97	43.99	5.139	4.315						
BeTe	136.61	68.31	5.626	5.090						
BePo	(2318)	(109)	5.838	7.3						
ZnO	81.39	40.69	4.63	5.675	2248	5.0 (M)	494	416	2.9	234
ZnS	97.46	48.72	5.4093	4.079	2100 (Tr. 1295)	1780	472	530	6.36	251

Substance	Molecular weight	Average atomic weight	Lattice parameters (Å, room temp.)	Density (g/cm ³)	Melting point (K)	Microhardness,	Specific	Debye temp. (K)	Coefficient of thermal linear expansion [10 ⁻⁶ K ⁻¹ (300K)]	Thermal conductivity [mW/cm·K (300K)]
						N/mm ² (M-Mohs Scale)	heat, J/kg·K (300 K)			
ZnSe	144.34	72.17	5.6676	5.42	1790	1350	339	400	7.2	140
ZnTe	192.99	96.5	6.101	6.34	1568	900	264	223	8.19	108
ZnPo	(274)	(137)	6.309							
CdS	144.48	72.24	5.832	4.826	1750	1250	330	219	4.7	200
CdSe	191.37	95.68	6.05	5.674	1512	1300	255	181	3.8	90
CdTe	240.01	120.00	6.477	5.86	1365	600	205	200	4.9	58.5
CdPo	(321)	(161)	6.665							
HgS	232.66	116.33	5.8517	7.73	1820	3 (M)	210			
HgSe	279.55	139.78	6.084	8.25	1070	2.5 (M)	178	151	5.46	10
HgTe	328.19	164.10	6.4623	8.17	943	300	164	242	4.6	20

III-V Compounds

BN	24.82	12.41	3.615	3.49	3239	10 (M)	793	≈1900		200
BP(L.T.)	41.78	20.87	4.538	2.9	1398 (dec)	37000		≈980		
BAs	85.73	42.87	4.777		≈2300	19000		≈625		
AIP	57.95	28.98	5.451	2.42	≈2100	5.5 (M)		588		920
AlAs	101.90	50.95	5.6622	3.81	2013	5000		417	3.5	840
AlSb	148.74	74.37	6.1355	4.218	1330	4000		292	4.2	600
GaP	100.70	50.35	5.4905	4.13	1750	9450		446	5.3	752
GaAs	144.64	72.32	5.65315	5.316	1510	7500		344	5.4	560
GaSb	191.48	95.74	6.0954	5.619	980	4480	320	265	6.1	270
InP	145.79	72.90	5.86875	4.787	1330	4100		321	4.6	800
InAs	189.74	94.87	6.05838	5.66	1215	3300	268	249	4.7	290
InSb	236.58	118.29	6.47877	5.775	798	2200	144	202	4.7	160

Other sphalerite structure compounds

MnS	87.00	43.5	5.011							
MnSe	133.90	66.95	5.82							
β-SiC (3-C SiC)	40.10	20.1	4.348	3.21	3070				2.9	4.9
Ga ₂ Se ₃	376.32	75.26	5.429	4.92	1020	3160			8.9	50
Ga ₂ Te ₃	522.24	104.45	5.899	5.75	1063	2370				47
In ₂ Te ₃ (H.T.)	608.44	121.7	6.173	5.8	940	1660				69
MgGeP ₂	158.84	39.71	5.652							
ZnSnP ₂	246.00	61.5	5.65		1200					
ZnSnAs ₂ (H.T.)	333.90	82.38	5.851	5.53	1050					76
ZnSnSb ₂	427.56	106.89	6.281	5.67	870	2500				76

1.1.3. Wurtzite (Zincite) Structure Compounds (Strukturbericht symbol B4, Space Group P 6₃mc-C_{6v}⁴)

I-VII Compounds

CuCl	99.0	49.5	3.91	6.42	703					
CuBr	143.45	71.73	4.06	6.66	770					
CuI	190.45	95.23	4.31	7.09						
AgI	234.77	117.40	4.580	7.494						

II-VI Compounds

BeO	25.01	12.51	2.698	4.380	2800					
MgTe	151.9	76.0	4.54	7.39	3.85	≈2800				
ZnO	81.37	40.69	3.24950	5.2069	5.66	2250				600
ZnS	97.43	48.72	3.8140	6.2576	4.1	2100				460

Substance	Molecular weight	Average atomic weight	Lattice parameters (Å, room temp.)		Density (g/cm ³)	Melting point (K)	Microhardness, N/mm ² (M-Mohs Scale)	Specific heat, J/kg·K (300 K)	Debye temp. (K)	Coefficient of thermal linear expansion [10 ⁻⁶ K ⁻¹ (300K)]	Thermal conductivity [mW/cm·K (300K)]
ZnTe	192.99	46.50	4.27	6.99		1568					
CdS	144.48	72.23	4.1348	6.7490	4.82	1748					401
CdSe	191.37	95.68	4.299	7.010	5.66	1512					316
CdTe	240.01	120.00	4.57	7.47							
III-V Compounds											
BP(H.T.)	41.79	20.90	3.562	5.900							
AlN	40.99	20.50	3.111	4.978	3.26	≈2500					823
GaN	83.73	41.87	3.190	5.189	6.10	1500					656
InN	128.83	64.42	3.533	5.693	6.88	1200					556
Other wurtzite structure compounds											
MnS	87.00	43.5	3.985	6.45	3.248						
MnSe	133.90	66.95	4.12	6.72							
SiC	40.10	20.1	3.076	5.048							
MnTe	182.54	91.27	4.078	6.701							
Al ₂ S ₃	150.14	30.03	3.579	5.829	2.55	1400					
Al ₂ Se ₃	290.84	58.17	3.890	6.30	3.91	1250					
<i>1.1.4. Chalcopyrite Structure Compounds (Strukturbericht symbol E1_p, Space Group I$\bar{4}$ 2d-D_{2d}¹²)</i>											
I-III-VI₂ Compounds											
CuAlS ₂	154.65	38.66	5.323	10.44	3.47	2500					
CuAlSe ₂	248.45	62.11	5.617	10.92	4.70	2260					
CuAlTe ₂	345.73	86.43	5.976	11.80	5.50	2550					
CuGaS ₂	197.39	49.53	5.360	10.49	4.35	2300					
CuGaSe ₂	291.19	72.80	5.618	11.01	5.56	1970	4200	275	5.4		42
CuGaTe ₂	388.47	97.12	6.013	11.93	5.99	2400	3500		6.9		27
CuInS ₂	242.49	60.62	5.528	11.08	4.75	1400	2550				
CuInSe ₂	336.29	84.07	5.785	11.56	5.77	1600	2050		6.6		37
CuInTe ₂	433.57	108.39	6.179	12.365	6.10	1660	400	195	7.1		49
CuTlS ₂	322.05	83.01	5.580	11.17	6.32						
CuTlSe ₂ (L.T.)	425.85	106.46	5.844	11.65	7.11	900					
CuFeS ₂	183.51	45.88	5.29	10.32	4.088	1135					
CuFeSe ₂	277.31	69.33				850					
CuLaS ₂	266.58	66.65	5.65	10.86							
AgAlS ₂	198.97	49.74	5.707	10.28	3.94						
AgAlSe ₂	292.77	73.19	5.968	10.77	5.07	1220					
AgAlTe ₂	390.05	97.51	6.309	11.85	6.18	1000					
AgGaS ₂	241.71	60.43	5.755	10.28	4.72						
AgGaSe ₂	335.51	83.88	5.985	10.90	5.84	1120	4400				
AgGaTe ₂	432.79	108.2	6.301	11.96	6.05	990	1800	212			10
AgInS ₂ (L.T.)	286.87	71.70	5.828	11.19	5.00		2250				
AgInSe ₂	380.61	95.15	6.102	11.69	5.81	1053	1850				30
AgInTe ₂	477.89	119.47	6.42	12.59	6.12	965			9.49, 0.69		
AgFeS ₂	227.83	56.96	5.66	10.30	4.53						
II-IV-V₂ Compounds											
ZnSiP ₂	155.40	38.85	5.400	10.441	3.39	1640	1100				
ZnGeP ₂	199.90	49.98	5.465	10.771	4.17	1295	8100				180
ZnSnP ₂	246.00	61.5					6500				
CdSiP ₂	202.43	50.61	5.678	10.431	4.00	≈1470	10500	282			

Substance	Molecular weight	Average atomic weight	Lattice parameters		Density (g/cm ³)	Melting point (K)	Microhardness, N/mm ² (M-Mohs Scale)	Specific heat, J/kg·K (300 K)	Debye temp. (K)	Coefficient of thermal linear expansion [10 ⁻⁶ K ⁻¹ (300K)]	Thermal conductivity [mW/cm·K (300K)]
			(Å, room temp.)								
CdGeP ₂	246.94	61.74	5.741	10.775	4.48	1049	5650				110
CdSnP ₂	243.03	73.26	5.900	11.518		840	5000		195		140
ZnSiAs ₂	242.20	60.55	5.61	10.88	4.70	1311	9200				
ZnGeAs ₂	287.80	71.95	5.672	11.153	5.32	1150	6800		263		110
ZnSnAs ₂	333.90	83.48	5.8515	11.704	5.53	1048	4550		271		150
CdSiAs ₂	290.34	72.58	5.884	10.882		>1120	6850				
CdGeAs ₂	334.83	83.71	5.9427	11.217	5.60	938	4700				48
			2								
CdSnAs ₂	380.93	95.23	6.0944	11.918	5.72	880	3450				40
			2								

1.1.5. Other Ternary Semiconductors with Tetrahedral Coordination

I ₂ -IV-VI ₃ Compounds											
Cu ₂ SiS ₃ (H.T.)	251.36	41.89	3.684	6.004	3.81	1200					23
Cu ₂ SiS ₃ (L.T.)			5.290	10.156	3.63						
Cu ₂ SiTe ₃	537.98	89.66	5.93		5.47						
Cu ₂ GeS ₃ (H.T.)	295.88	49.31	5.317		4.45	1210	4550	510	254	7.2	12
Cu ₂ GeS ₃ (L.T.)			5.327	5.215	4.46						
Cu ₂ GeSe ₃	436.56	72.76	5.589	5.485	5.57	1030	3840	340	168	8.4	24
Cu ₂ GeTe ₃	582.51	97.09	5.958	5.935	5.92		2890				130
Cu ₂ SnS ₃	341.98	57.00	5.436		5.02	1110	2770	440	214	7.8	28
CuSnSe ₃	482.66	80.44	5.687		5.94	960	2510	310	148	8.9	35
Cu ₂ SnTe ₃	628.61	104.77	6.048		6.51	680	1970				144
Ag ₂ GeSe ₃	525.21	87.54				810					
Ag ₂ SnSe ₃	571.31	95.22									
Ag ₂ GeTe ₃	671.13	111.86				600					
Ag ₂ SnTe ₃	717.23	119.54									
I ₃ -V -VI ₄ -Compounds											
Cu ₃ PS ₄	349.85	40.73	7.44	6.19							
Cu ₃ AsS ₄	393.79	49.22	6.43	6.14	4.37	931				3.2	30.2
Cu ₃ AsSe ₄	581.37	72.67	5.570	10.957	5.61	733			169	9.5	19
Cu ₃ SbS ₄	440.64	55.08	5.38	16.76	4.90	830					
Cu ₃ SbSe ₄	628.22	78.53	5.654	11.256	6.0	700			131	12.4	14.6
I-IV ₂ -V ₃ Compounds											
CuSi ₂ P ₃	212.64	35.44	5.25								
CuGe ₂ P ₃	301.65	50.28	5.375		4.318	1113	8500	429	8.21	37.6	
AgGe ₂ P ₃	345.97	57.66				1015	6150				

1.1.6. "Defect Chalcopyrite" Structure Compounds (Strukturbericht symbol E3, Space Group I $\bar{4}$ -S₆²)

ZnAl ₂ Se ₄	435.18	62.17	5.503	10.90	4.37						
ZnAl ₂ Te ₄ (?)	629.74	84.96	5.904	12.05	4.95						
ZnGa ₂ S ₄ (?)	333.06	47.58	5.274	10.44	3.80						
ZnGa ₂ Se ₄ (?)	520.66	74.38	5.496	10.99	5.21						
ZnGa ₂ Te ₄ (?)	715.22	102.17	5.937	11.87	5.67						
ZnIn ₂ Se ₄	610.86	87.27	5.711	11.42	5.44	1250					
ZnIn ₂ Te ₄	805.42	115.06	6.122	12.24	5.83	1075					
CdAl ₂ S ₄	294.61	42.09	5.564	10.32	3.06						
CdAl ₂ Se ₄	482.21	68.89	5.747	10.68	4.54						
CdAl ₂ Te ₄ (?)	676.77	97.68	6.011	12.21	5.10						

Substance	Molecular weight	Average atomic weight	Lattice parameters (Å, room temp.)		Density (g/cm ³)	Melting point (K)	Microhardness, N/mm ² (M-Mohs Scale)	Specific heat, J/kg·K (300 K)	Debye temp. (K)	Coefficient of thermal linear expansion [10 ⁻⁶ K ⁻¹ (300K)]	Thermal conductivity [mW/cm·K (300K)]
CdGa ₂ S ₄	380.09	54.30	5.577	10.08	4.03						
CdGa ₂ Se ₄	567.69	81.10	5.743	10.73	5.32						
CdGa ₂ Te ₄	762.25	108.89	6.093	11.81	5.77						
CdIn ₂ Te ₄	852.45	121.78	6.205	12.41	5.9	1060					
HgAl ₂ S ₄	382.79	54.68	5.488	10.26	4.11						
HgAl ₂ Se ₄	570.39	82.48	5.708	10.74	5.05						
HgAl ₂ Te ₄ (?)	764.48	109.28	6.004	12.11	5.81						
HgGa ₂ S ₄	468.27	66.90	5.507	10.23	5.00						
HgGa ₂ Se ₄	655.87	93.70	5.715	10.78	6.18						
HgIn ₂ Se ₄	746.07	106.58	5.764	11.80	6.3	1100					
HgIn ₂ Te ₄ (?)	940.63	134.38	6.186	12.37	6.3	980					

1.1.7. Other Adamantine Compounds

α-SiC	40.10	20.10	3.0817	15.12	3.21	3070					
Hg ₅ Ga ₂ Te ₈	2163.19	144.21	6.235								
Hg ₅ In ₂ Te ₈	2253.39	150.23	6.328								
CdIn ₂ Se ₄	657.89	93.98	a = c = 5.823								

1.2. Octahedral Semiconductors

1.2.1. Halite Structure Semiconductors (Strukturbericht symbol B1, Space Group Fm3m-O_h⁵)

GeTe	200.21	100.10	5.98		6.14						
SnSe	197.67	98.83	6.020			1133					
SnTe	246.31	123.15	6.313		6.45	1080 (max)					91
PbS	239.3	119.63	5.9362		7.61	1390					23
PbSe	286.2	143.08	6.1243		8.15	1340					17
PbTe	334.8	167.4	6.454		8.16	1180					23

1.2.2. Selected Other Binary Halites

BiSe	287.94	143.97	5.99		7.98	880					
BiTe	336.58	168.29	6.47								
EuSe	230.92	115.46	6.191			2300					2.4
GdSe	236.21	118.11	5.771			2400					
NiO	74.69	37.35	4.1684		6.6	2260					
CdO	128.41	64.21	4.6953			1700					7
SrS	119.69	59.84	6.0199		3.643	3000					

1.3. Other Semiconductors

1.3.1. Antifluorite Structure Compounds (Fm3m-O_h⁵)

Mg ₂ Si	76.70	25.57	6.338		1.88	1375			11.5		
Mg ₂ Ge	121.22	40.4	6.380		3.08	1388			15.0		
Mg ₂ Sn	167.32	55.77	6.765		3.53	1051			9.9		92
Mg ₂ Pb	225.81	85.27	6.836		5.1	823			10.0		

1.3.2. Tetradymite Structure Compounds ($\bar{R}3m-D_{3d}^5$)

Sb ₂ Te ₃	626.3	125.26	4.25	30.3	6.44	895					
Bi ₂ Se ₃	654.84	130.97	4.14	28.7	7.51	979	167				24
Bi ₂ Te ₃	800.76	160.15	4.38	30.45	7.73	858	155	16			30

Substance	Molecular weight	Average atomic weight	Lattice parameters (Å, room temp.)	Density (g/cm ³)	Melting point (K)	Microhardness, N/mm ² (M-Mohs Scale)	Specific heat, J/kg·K (300 K)	Debye temp. (K)	Coefficient of thermal linear expansion [10 ⁻⁶ K ⁻¹ (300K)]	Thermal conductivity [mW/cm·K (300K)]	
1.3.3. Skutterudite Structure Compounds (<i>Im</i>3-<i>T_h</i>⁵)											
CoP ₃	151.85	37.96	7.7073		>1270						
CoAs ₃	286.70	71.65	8.2060	6.73	1230						
CoSb ₃	424.18	106.05	9.0385		1123			307		50	
NiAs ₃	283.45	70.86	8.330	6.43							
RhP ₃	195.83	48.96	7.9951		>1470						
RhAs ₃	327.67	81.92	8.4427		>1270					100	
RhSb ₃	468.16	117.04	9.2322		1170						
IrP ₃	285.14	71.29	8.0151	7.36	>1470						
IrAs ₃	416.98	104.25	8.4673	9.12	>1470					90	
IrSb ₃	557.47	139.37	9.2533	9.35	1170			303			
1.3.4. Selected Multinary Compounds											
AgSbSe ₂	387.54	96.88	5.786	6.60	910					10.5	
AgSbTe ₂ (or Ag ₁₉ Sb ₂₉ Te ₅₂)	484.82	121.2	6.078	7.12	830					86	
AgBiS ₂ (H.T.)	380.97	95.24	5.648								
AgBiSe ₂ (H.T.)	474.77	118.69	5.82								
AgBiTe ₂ (H.T.)	572.05	143.01	6.155								
Cu ₂ CdSnS ₄	486.43	60.80	5.586	10.83							
1.3.5. Some Elemental Semiconductors											
B		10.81	4.91	12.6	2.34	2348	9.5 (M)	1277	1370	8.3	600
Se(gray)		78.96	4.36	4.95	4.81	493	350	292.6		(C) 17.89 (⊥C) 74.09	(C) 45.2 (⊥C) 13.1
Te		127.60	4.45	5.91	6.23	723		196.5		16.8	(C) 33.8 (⊥C) 19.7

TABLE 2. Basic Thermodynamic, Electrical, and Magnetic Properties of Semiconductors (Listed by Crystal Structure)

Substance	Heat of formation [kJ/mol (300K)]	Volume compressibility (10 ⁻¹⁰ m ² /N)	Static dielectric constant	Atomic magnetic susceptibility (10 ⁻⁶ cgs)	Index of refraction	Minimum room temperature energy gap (eV)	Mobility (room temp.) (cm ² /V·s)		Optical transition	Breakdown voltage kV/mm	Remarks
							Electrons	Holes			
2.1. Adamantine Semiconductors											
2.1.1. Diamond Structure Elements (Strukturbericht symbol A4, Space Group <i>Fd</i> 3<i>m</i>-<i>O_h</i>⁷)											
C	714.4	18	5.7	-5.88	2.419 (589 nm)	5.4	1800	1400	i*	500	
Si	324	0.306	11.9	-3.9	3.49 (589 nm)	1.12	1900	500	i	30	
Ge	291	0.768	16	-0.12	3.99 (589 nm)	0.67	3800	1820	i		
α-Sn	267.5		24		2.75 (589 nm)	0.0; 0.8	2500	2400			
2.1.2. Sphalerite (Zinc Blende) Structure Compounds (Strukturbericht symbol B3 Space Group <i>F</i> 4 3<i>m</i>-<i>T_d</i>²)											
I-VII Compounds											
CuF											
CuCl	481	0.26	7.9		1.93	3.17			d		Nantokite

Substance	Heat of formation [kJ/mol (300K)]	Volume compressibility ($10^{-10}\text{m}^2/\text{N}$)	Static dielectric constant	Atomic magnetic susceptibility (10^{-6}cgs)	Index of refraction	Minimum room temperature energy gap (eV)	Mobility (room temp.) ($\text{cm}^2/\text{V}\cdot\text{s}$)		Optical transition	Breakdown voltage kV/mm	Remarks
							Electrons	Holes			
CdS				8.45; 9.12	2.32	2.42	350	40	d		Greenockide
CdSe						1.74	900	50	d		Cadmioselite
CdTe						1.50	650				
III-V Compounds											
BP(H.T.)											
AlN						6.02					
GaN						3.34					
InN						2.0					
Other wurtzite structure compounds											
MnS											
MnSe											
SiC					2.654						
MnTe						≈ 1.0					
Al ₂ S ₃	426					4.1					
Al ₂ Se ₃	367					3.1					
2.1.4 Chalcopyrite Structure Compounds (Strukturbericht symbol $E1_p$, Space Group $I\bar{4}2d-D_{2d}^{12}$)											
I-III-VI₂ Compounds											
CuAlS ₂		0.106				2.5					
CuAlSe ₂						2.67					
CuAlTe ₂						0.88					
CuCaS ₂		0.106				2.38					
CuGaSe ₂		0.141				0.96, 1.63					
CuGaTe ₂		0.227				0.82, 1.0					
CuInS ₂		0.141				1.2					
CuInSe ₂		0.187				0.86, 0.92					
CuInTe ₂		0.278				0.95					
CuTlS ₂											
CuTlSe ₂						1.07					
(L.T.)											
CuFeS ₂						0.53					Chalcopyrite
CuFeSe ₂						0.16					
CuLaS ₂											
AgAlS ₂											
AgAlSe ₂						0.7					
AgAlTe ₂						0.56					
AgGaS ₂		0.150				1.66					
AgGaSe ₂		0.182				1.1					
AgGaTe ₂		0.280				1.9					
AgInS ₂		0.185				1.18					
(L.T.)											
AgInSe ₂		0.238				0.96, 0.52					
AgInTe ₂		0.338									
AgFeS ₂											
II-IV-V₂ Compounds											
ZnSiP ₂	312					2.3	1000				
ZnGeP ₂	293					2.2					
ZnSnP ₂	275					1.45					
CdSiP ₂		0.103				2.2	1000				
CdGeP ₂	289					1.8					
CdSnP ₂	270					1.5					
ZnSiAs ₂	290					1.7		50			
ZnGeAs ₂	271			-14.4		0.85					
ZnSnAs ₂	252			-18.4		0.65		300			Disorders at 910 K
CdSiAs ₂		0.143				1.6					
CdGeAs ₂	266			-23.4		0.53	70	25			Disorders at 903 K
CdSnAs ₂	247		13.7	-21.5		0.26	22000	250			

Substance	Heat of formation [kJ/mol (300K)]	Volume compressibility (10 ⁻¹⁰ m ² /N)	Static dielectric constant	Atomic magnetic susceptibility (10 ⁻⁶ cgs)	Index of refraction	Minimum room temperature energy gap (eV)	Mobility (room temp.) (cm ² /V·s)		Optical transition	Breakdown voltage kV/mm	Remarks
							Electrons	Holes			

2.1.5. Other Ternary Semiconductors with Tetrahedral Coordination

II₂-IV-VI₃ Compounds

Cu ₂ SiS ₃ (H.T.)											Wurtzite
Cu ₂ SiS ₃ (L.T.)											Tetragonal
Cu ₂ SiTe ₃											Cubic
Cu ₂ GeS ₃ (H.T.)				-18.7							Cubic
Cu ₂ GeS ₃ (L.T.)								360			Tetragonal
Cu ₂ GeSe ₃	211.5			-21.3		0.94		238			Same
Cu ₂ GeTe ₃	190.2			-23.4							Same
Cu ₂ SnS ₃				-18.2		0.91		405			Cubic
CuSnSe ₃				-21.0		0.66		870			Cubic
Cu ₂ SnTe ₃				-28.4							Cubic
Ag ₂ GeSe ₃				-29.6				0.91 (77K)			
Ag ₂ SnSe ₃				-29.5		0.81					
Ag ₂ GeTe ₃				-31.4		0.25					
Ag ₂ SnTe ₃				-31.0		0.08					

II₃-V-VI₄ Compounds

Cu ₃ PS ₄											Enargite
Cu ₃ AsS ₄	269.6			-15.8		1.24					
Cu ₃ AsSe ₄	161.3			-13.1		0.88					Famatinite
Cu ₃ SbS ₄				-8.3		0.74					Famatinite
Cu ₃ SbSe ₄	127.1			-20.5		0.31					

II-IV₂-V₃ Compounds

CuSi ₂ P ₃											El
CuGe ₂ P ₃		0.12				0.90					El
AgGe ₂ P ₃											

2.1.6. "Defect Chalcopyrite" Structure Compounds (Strukturbericht symbol E3, Space Group I $\bar{4}$ -S₄²)

ZnAl ₂ Se ₄											
ZnAl ₂ Te ₄ (?)											
ZnGa ₂ S ₄ (?)						≈3.4					
ZnGa ₂ Se ₄ (?)						≈2.2					
ZnGa ₂ Te ₄ (?)						1.35					
ZnIn ₂ Se ₄	206					1.82		35			
ZnIn ₂ Te ₄	198					1.2					
CdAl ₂ S ₄											
CdAl ₂ Se ₄											
CdAl ₂ Te ₄ (?)											
CdGa ₂ S ₄	256					3.44		60			
CdGa ₂ Se ₄	216					2.43		33			
CdGa ₂ Te ₄											
CdIn ₂ Te ₄	195					(1.26 or 0.9)		4000			
HgAl ₂ S ₄											
HgAl ₂ Se ₄											
HgAl ₂ Te ₄ (?)											
HgGa ₂ S ₄	249					2.84					
HgGa ₂ Se ₄	204					1.95		400			
HgIn ₂ Se ₄	196					0.6		290			
HgIn ₂ Te ₄ (?)	188					0.86		200			

2.1.7. Other Adamantine Compounds

α-SiC			10.2	-6.4	2.67	2.86		400			6H structure
Hg ₃ Ga ₂ Te ₈											B3 with superlattice
Hg ₃ In ₂ Te ₈						0.7		2000			B3 with superlattice
CdIn ₂ Se ₄						1.55					

Substance	Heat of formation [kJ/mol (300K)]	Volume compressibility (10 ⁻¹⁰ m ² /N)	Static dielectric constant	Atomic magnetic susceptibility (10 ⁻⁶ cgs)	Index of refraction	Minimum room temperature energy gap (eV)	Mobility (room temp.) (cm ² /V·s)		Optical transition	Breakdown voltage kV/mm	Remarks
							Electrons	Holes			
2.2. Octahedral Semiconductors											
2.2.1. Halite Structure Semiconductors (Strukturbericht symbol B1, Space Group Fm3m-O_h⁵)											
GeTe											
SnSe											
SnTe											
PbS	435					0.5	600	600			
PbSe	393		161			0.37	1000	900			
PbTe	393		280			0.26	1600	600			Altaite
			360			0.25					
2.2.2. Selected Other Binary Halites											
BiSe											
BiTe						0.4					
EuSe											
GdSe						1.8	4				
NiO						2.0 or 3.7	100				
CdO	531					2.5					
SrS						4.1					
2.3. Other Semiconductors											
2.3.1. Antifluorite Structure Compounds (Fm3m-O_h⁵)											
Mg ₂ Si	79.08					0.77	405	70			
Mg ₂ Ge						0.74	520	110			
Mg ₂ Sn	76.57					0.36	320	260			
Mg ₂ Pb	52.72					0.1					
2.3.2. Tetradymite Structure Compounds (R3m-D_{3d}⁵)											
Sb ₂ Te ₃						0.3		360			
Bi ₂ Se ₃						0.35	600				
Bi ₂ Te ₃						0.21	1140	680			R3m (166)
2.3.3. Skutterudite Structure Compounds (Im3-T_h⁵)											
CoP ₃						0.43					
CoAs ₃						0.69		~4000			
CoSb ₃						0.63	70	~3000			
RhP ₃								700			
RhAs ₃						0.85		~3000			
RhSb ₃						0.80		~7000			
IrSb ₃						1.18		1500			
2.3.4. Selected Multinary Compounds											
AgSbSe ₂						0.58					
AgSbTe ₂						0.7, 0.27					
(or Ag ₁₉ Sb ₂₉ Te ₅₂)											
AgBiS ₂ (H.T.)											
AgBiSe ₂ (H.T.)											
AgBiTe ₂ (H.T.)											
Cu ₂ CdSnS ₄						1.16	<2				
2.3.5. Some Elemental Semiconductors											
B	397.1			-6.7	3.4	1.55	10				
Se(gray)			6.6	-22.1	2.5	1.5		5			P3 ₁ 21(152)
			(0.1 GHz)								
Te				-39.5	3.3	0.33	1700	1200			Same

TABLE 4. Band Properties of Semiconductors

4.1. Data on Valence Bands of Semiconductors (Room Temperature)

Substance	Band curvature effective mass (Expressed as fraction of free electron mass)			Energy separation of "split-off" band (eV)	Measured (light) hole mobility (cm ² /V·s)
	Heavy holes	Light holes	"Split-off" band holes		
<i>4.1.1. Semiconductors with Valence Band Maximum at the Center of the Brillouin Zone ("F")</i>					
Si	0.52	0.16	0.25	0.044	500
Ge	0.34	0.043	0.08	0.3	1820
Sn	0.3				2400
AlAs					
AlSb	0.4			0.7	550
GaP				0.13	100
GaAs	0.8	0.12	0.20	0.34	400
GaSb	0.23	0.06		0.7	1400
InP				0.21	150
InAs	0.41	0.025	0.083	0.43	460
InSb	0.4	0.015		0.85	750
CdTe	0.35				50
HgTe	0.5				350

4.1.2. Semiconductors with Multiple Band Maxima

Substance	Number of equivalent valleys and direction	Band curvature effective masses		Anisotropy $K = m_L/m_T$	Measured (light) hole mobility (cm ² /V·s)
		Longitudinal m_L	Transverse m_T		
PbSe	4 "L" [111]	0.095	0.047	2.0	1500
PbTe	4 "L" [111]	0.27	0.02	10	750
Bi ₂ Te ₃	6	0.207	~0.045	4.5	515

4.2. Data on Conduction Bands of Semiconductors (Room Temperature Data)

4.2.1. Single Valley Semiconductors

Substance	Energy gap (eV)	Effective mass (m_o)	Mobility (cm ² /V·s)	Comments
GaAs	1.35	0.067	8500	3(or 6?) equivalent [100] valleys 0.36 eV above this maximum with a mobility of ~50.
InP	1.27	0.067	5000	3(or 6?) equivalent [100] valleys 0.4 eV above this minimum.
InAs	0.36	0.022	33,000	Equivalent valleys ~1.0 eV above this minimum.
InSb	0.165	0.014	78,000	
CdTe	1.44	0.11	1000	4(or 8?) equivalent [111] valleys 0.51 eV above this minimum.

4.2.2. Multivalley Semiconductors

Substance	Energy gap	Number of equivalent valleys and direction	Band curvature effective mass		Anisotropy $K = m_L/m_T$
			Longitudinal m_L	Transverse m_T	
Si	1.107	6 in [100] "Δ"	0.00	0.192	4.7
Ge	0.67	4 in [111] at "L"	1.588	0.0815	19.5
GaSb	0.67	as Ge (?)	~1.0	~0.2	~5
PbSe	0.26	4 in [111] at "L"	0.085	0.05	1.7
PbTe	0.25	4 in [111] at "L"	0.21	0.029	5.5
Bi ₂ Te ₂	0.13	6			~0.05

TABLE 5. Resistivity of Semiconducting Minerals

Mineral	ρ (ohm · m)	Mineral	ρ (ohm · m)
Diamond (C)	2.7	Pentlandite, (Fe, Ni) ₄ S ₄	1 to 11 × 10 ⁻⁶
Sulfides		Pyrrhotite, Fe ₇ S ₄	2 to 160 × 10 ⁻⁶
Argentite, Ag ₂ S	1.5 to 2.0 × 10 ⁻³	Pyrite, FeS ₂	1.2 to 600 × 10 ⁻³
Bismuthinite, Bi ₂ S ₃	3 to 570	Sphalerite, ZnS	2.7 × 10 ⁻³ to 1.2 × 10 ⁴
Bornite, Fe ₂ S ₃ · nCu ₂ S	1.6 to 6000 × 10 ⁻⁶	Antimony-sulfur compounds	
Chalcocite, Cu ₂ S	80 to 100 × 10 ⁻⁶	Berthierite, FeSb ₂ S ₄	0.0083 to 2.0
Chalcopyrite, Fe ₂ S ₃ · Cu ₂ S	150 to 9000 × 10 ⁻⁶	Boulangerite, Pb ₅ Sb ₃ S ₁₁	2 × 10 ³ to 4 × 10 ⁴
Covellite, CuS	0.30 to 83 × 10 ⁻⁶	Cylindrite, Pb ₃ Sn ₄ Sb ₂ S ₁₄	2.5 to 60
Galena, PbS	6.8 × 10 ⁻⁶ to 9.0 × 10 ⁻²	Franckeite, Pb ₃ Sn ₃ Sb ₂ S ₁₄	1.2 to 4
Haverite, MnS ₂	10 to 20	Hauchecornite, Ni ₄ (Bi, Sb) ₂ S ₁₄	1 to 83 × 10 ⁻⁶
Marcasite, FeS ₂	1 to 150 × 10 ⁻³	Jamesonite, Pb ₄ FeSb ₆ S ₁₄	0.020 to 0.15
Metacinnabarite, HgS	2 × 10 ⁻⁶ to 1 × 10 ⁻³	Tetrahedrite, Cu ₃ SbS ₃	0.30 to 30,000
Millerite, NiS	2 to 4 × 10 ⁻⁷	Arsenic-sulfur compounds	
Molybdenite, MoS ₂	0.12 to 7.5	Arsenopyrite, FeAsS	20 to 300 × 10 ⁻⁶

Cobaltite, CoAsS	6.5 to 130×10^{-3}	Hessite, Ag ₂ Te	4 to 100×10^{-6}
Enargite, Cu ₃ AsS ₄	0.2 to 40×10^{-3}	Nagyagite, Pb ₆ Au(S,Te) ₁₄	20 to 80×10^{-6}
Gersdorffite, NiAsS	1 to 160×10^{-6}	Sylvanite, AgAuTe ₄	4 to 20×10^{-6}
Glauco-dote, (Co, Fe)AsS	5 to 100×10^{-6}	Oxides	
Antimonide		Braunite, Mn ₂ O ₃	0.16 to 1.0
Dyscrasite, Ag ₃ Sb	0.12 to 1.2×10^{-6}	Cassiterite, SnO ₂	4.5×10^{-4} to 10,000
Arsenides		Cuprite, Cu ₂ O	10 to 50
Allemonite, SbAs ₃	70 to 60,000	Hollandite, (Ba, Na, K) Mn ₈ O ₁₆	2 to 100×10^{-3}
Lollingite, FeAs ₂	2 to 270×10^{-6}	Ilmenite, FeTiO ₃	0.001 to 4
Nicollite, NiAs	0.1 to 2×10^{-6}	Magnetite, Fe ₃ O ₄	52×10^{-6}
Skutterudite, CoAs ₃	1 to 400×10^{-6}	Manganite, MnO · OH	0.018 to 0.5
Smaltite, CoAs ₂	1 to 12×10^{-6}	Melaconite, CuO	6000
Tellurides		Psilomelane, BaMn ₉ O ₁₈ · 2H ₂ O	0.04 to 6000
Altaite, PbTe	20 to 200×10^{-6}	Pyrolusite, MnO ₂	0.007 to 30
Calavarite, AuTe ₂	6 to 12×10^{-6}	Rutile, TiO ₂	29 to 910
Coloradoite, HgTe	4 to 100×10^{-6}	Uraninite, UO ₂	1.5 to 200

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